Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/648,172	LEE, SUNG-KWON
Examiner	Art Unit
Kin-Chan Chen	1765

SEARCHED						
Cli	ass	Subclass	Date		Examiner	
438		706	6/30/2005		ксс	
		712				
	ĺ	719				
		720				
		723				
		724				
4	38	725	6/3	105	Kc	C
	0					
				_		
-						

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		-	-		
	į				
			1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST key words search, USPAT, USPGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search.	6/30/2005	ксс		
ı				
	40			